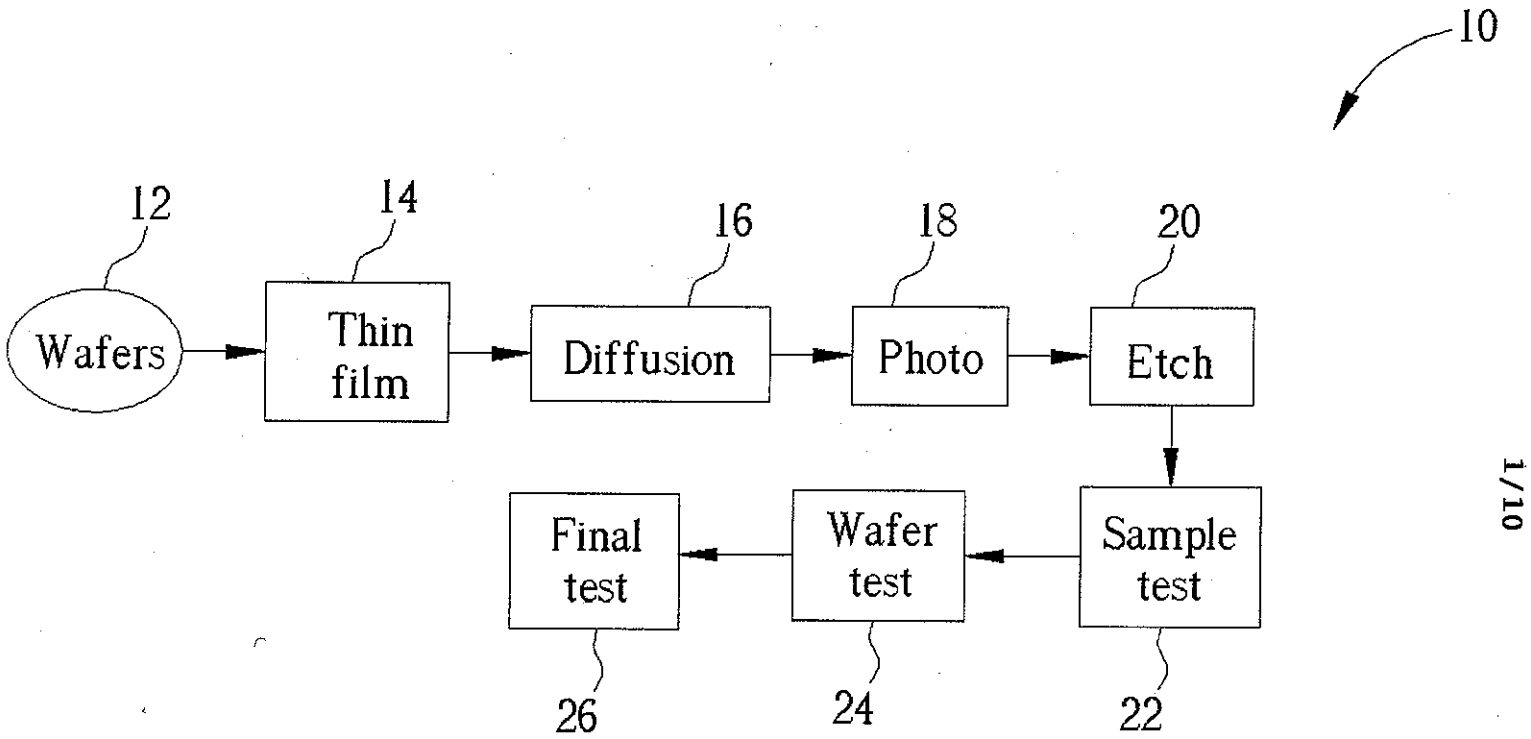


Fig. 1 Prior Art

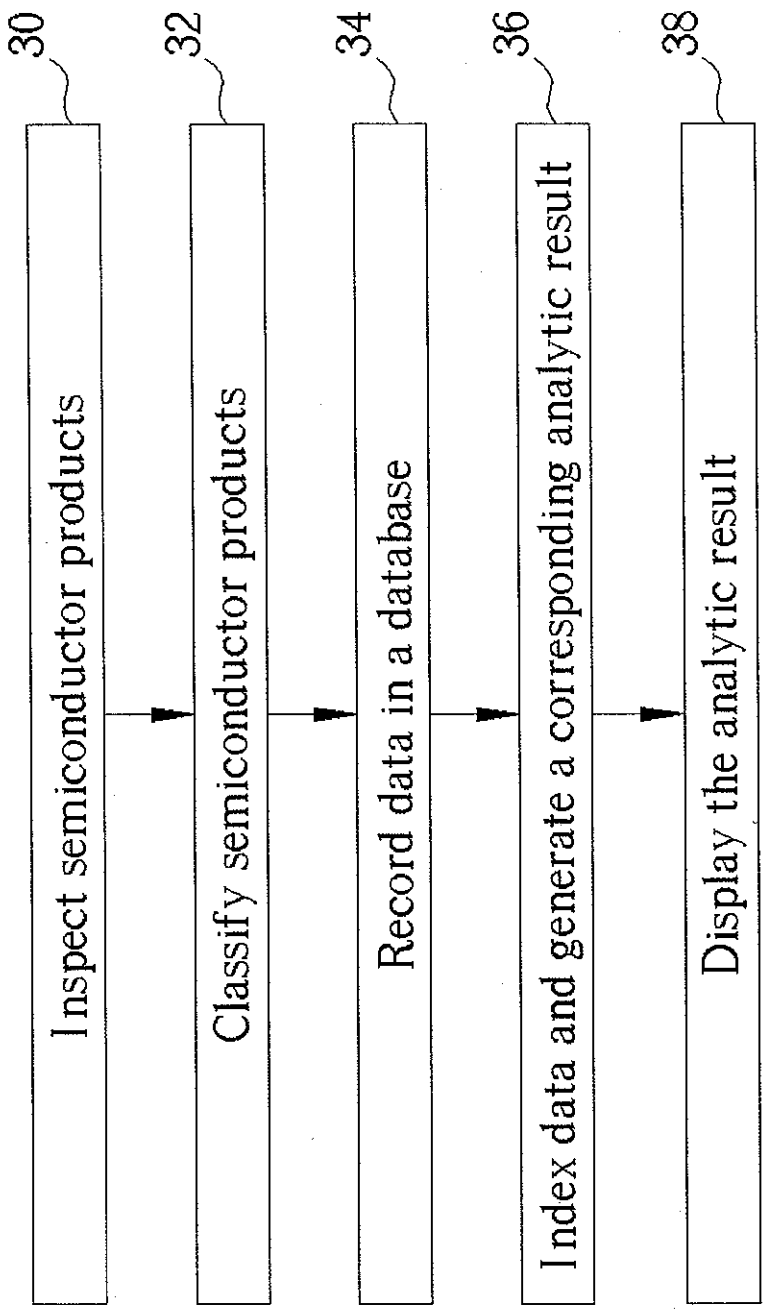

30
Inspect semiconductor products
32
Classify semiconductor products
34
Record data in a database
36
Index data and generate a corresponding analytic result
38
Display the analytic result

Fig. 2

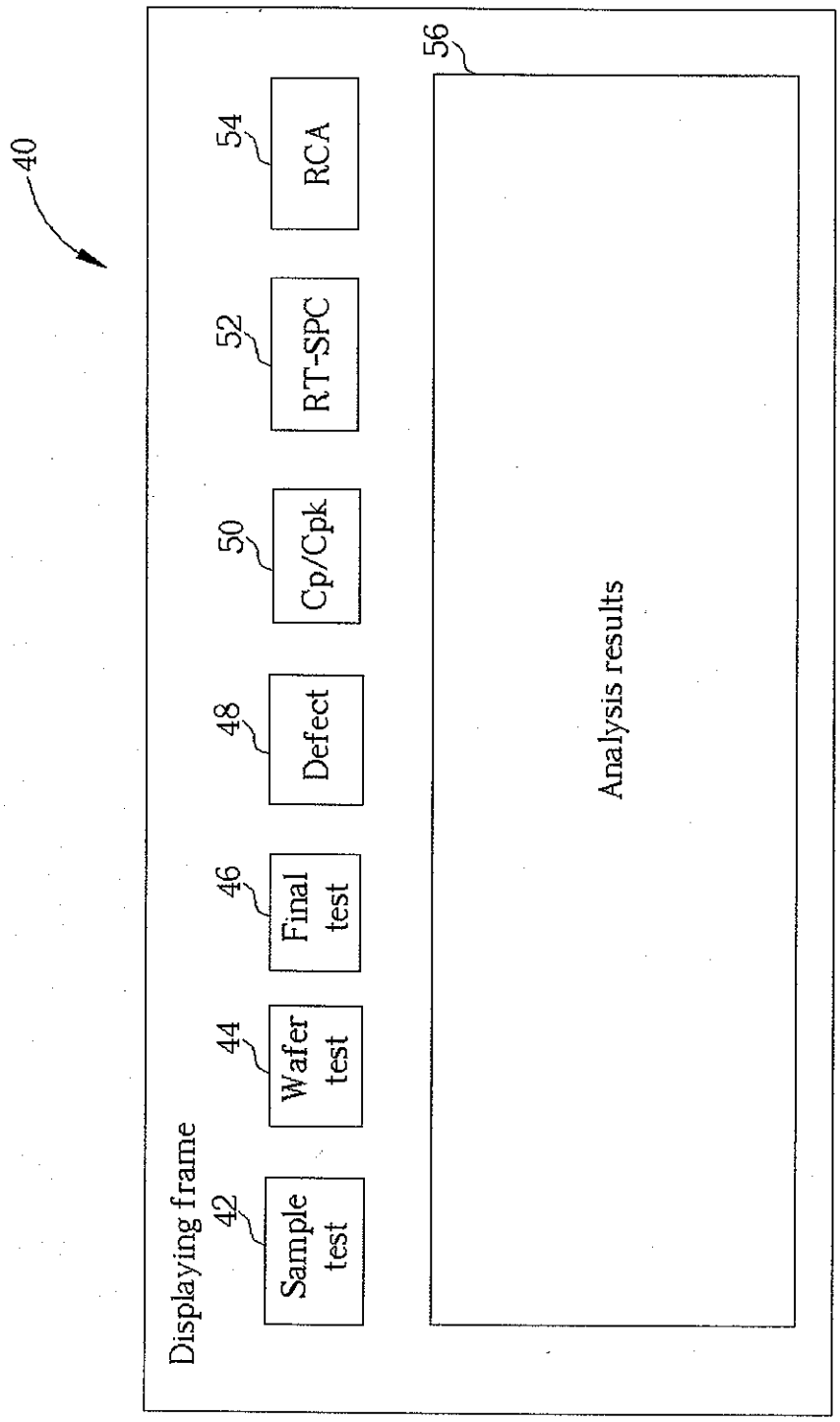

40
Displaying frame
42
Sample test
44
Wafer test
46
Final test
48
Defect
50
Cp/Cpk
52
RT-SPC
54
RCA
56
Analysis results

Fig. 3

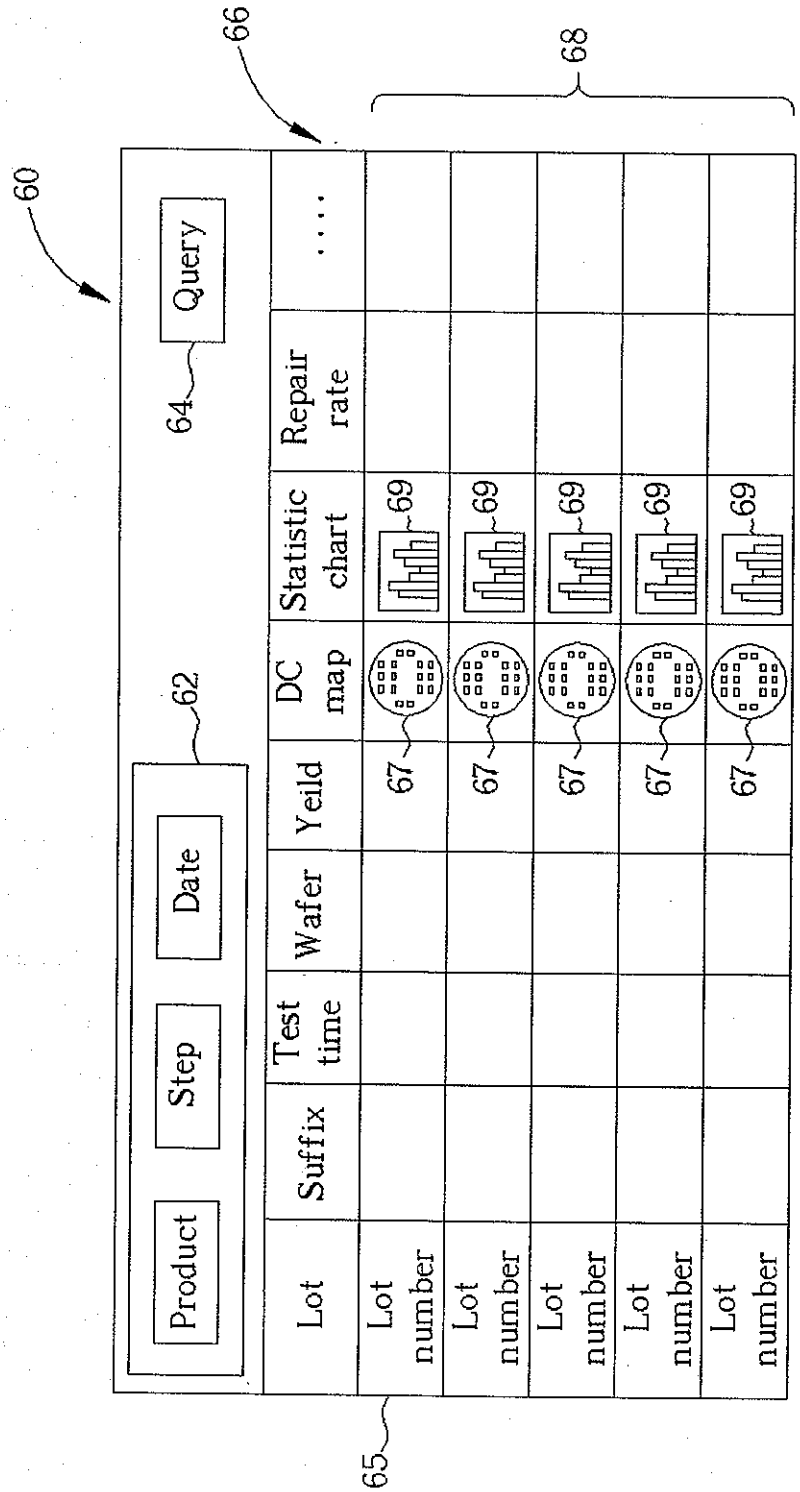

60
66
68
Query
64
Product
Step
Date
62
Lot
Suffix
Test time
Wafer
Yeild
DC map
Statistic chart
Repair rate
.....
Lot number
65
67
69

Fig. 4

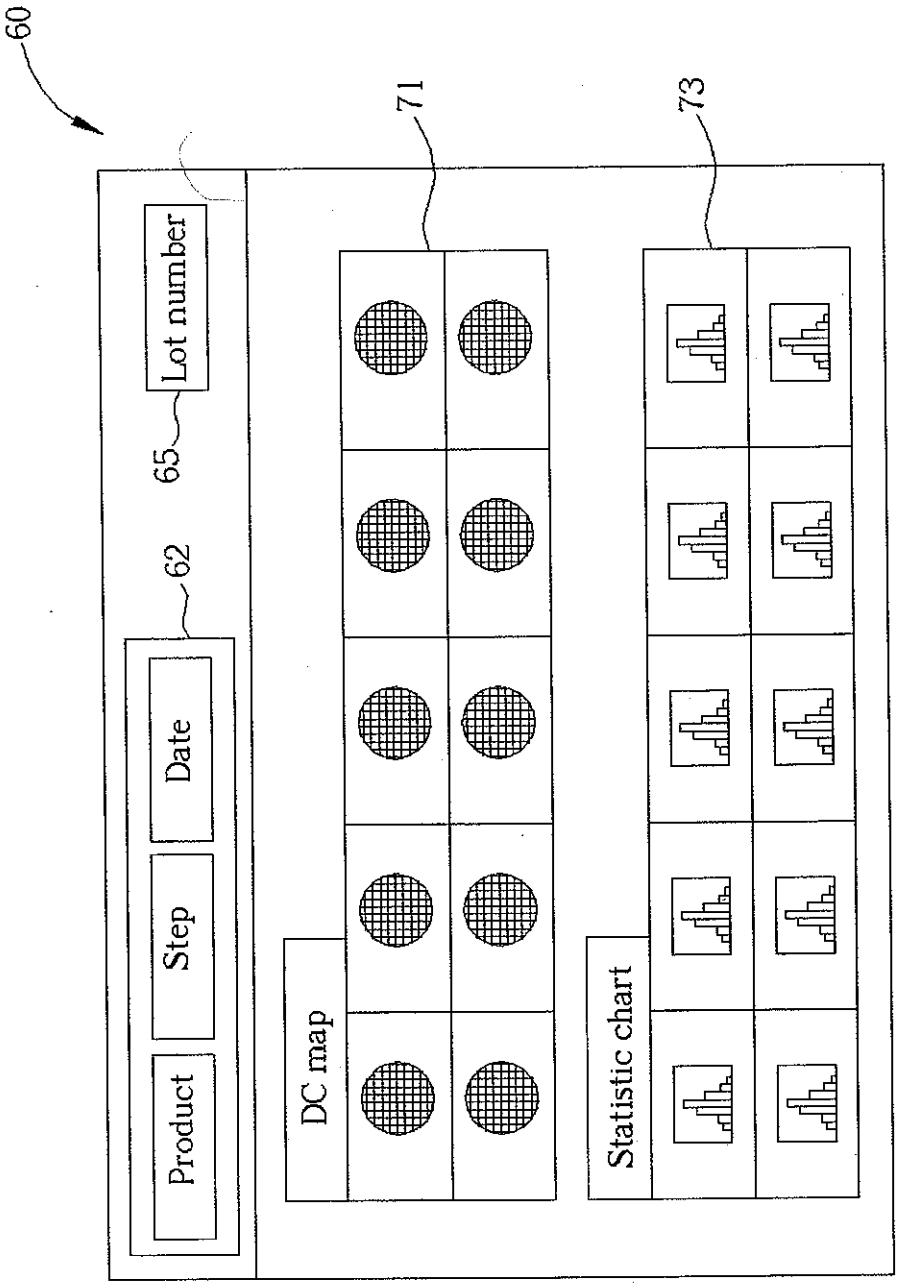

60
71
73
Lot number
65
62
Product
Step
Date
DC map
Statistic chart

Fig. 5

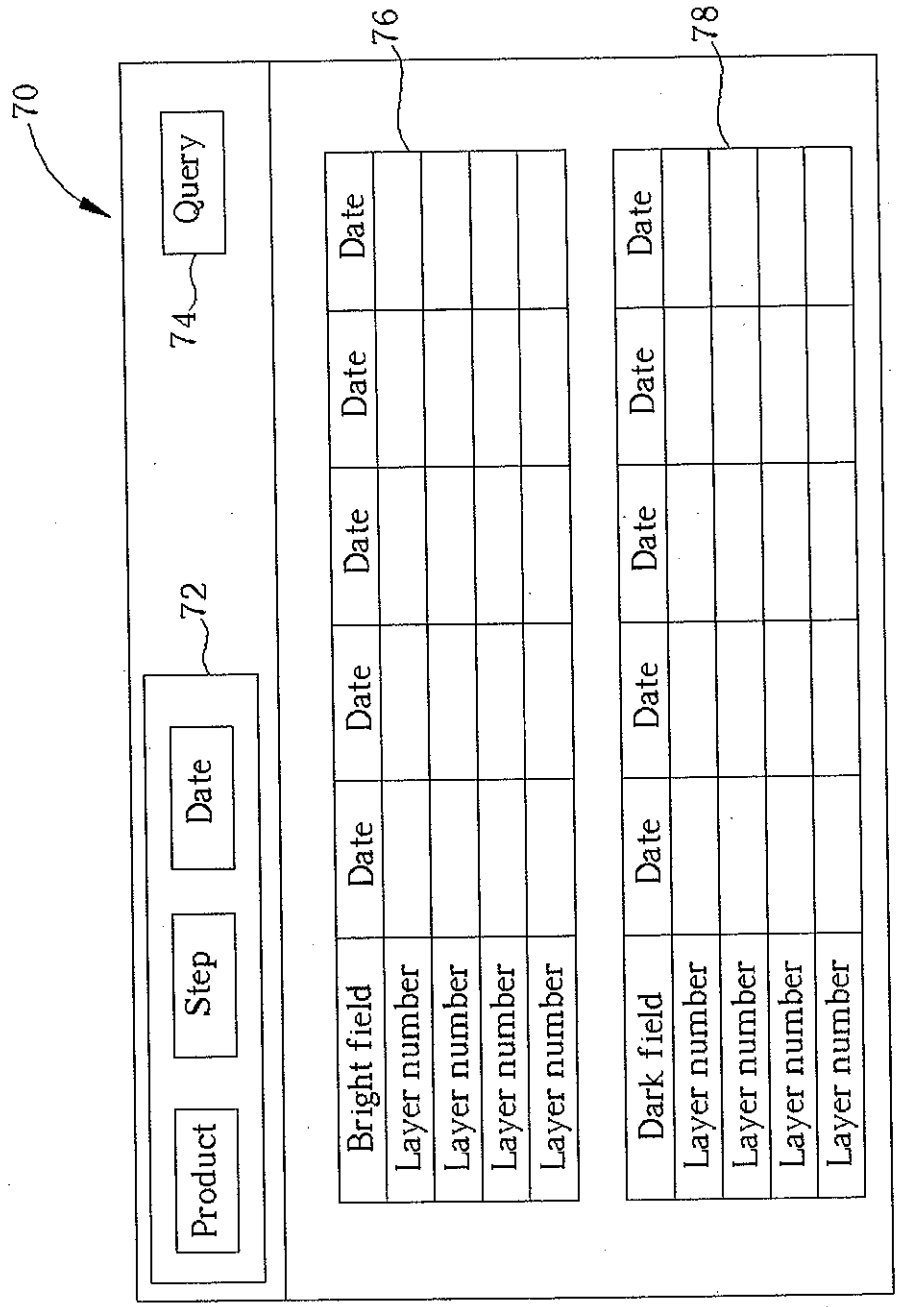

70
Product
Step
Date
72
Query
74
76
Bright field
Date
Layer number
78
Dark field

Fig. 6

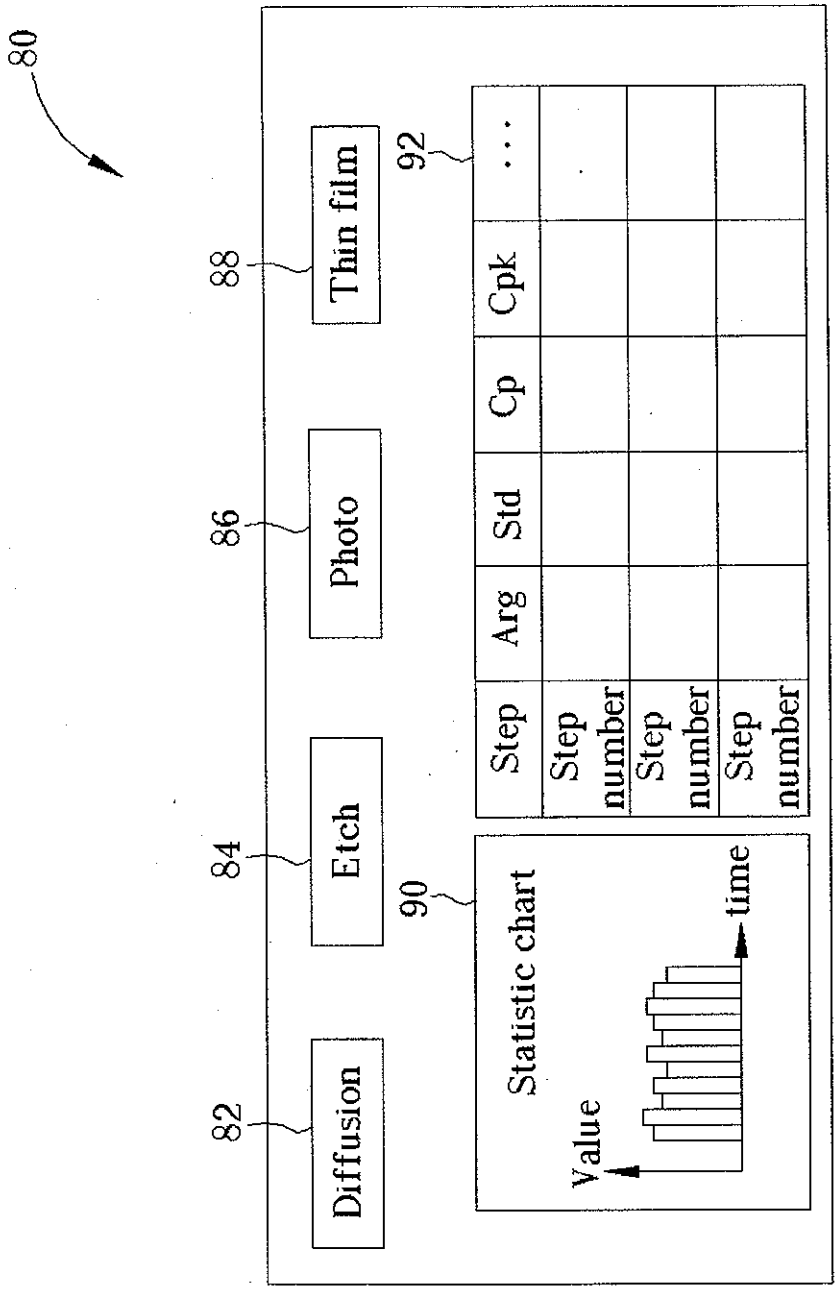

80
82
Diffusion
84
Etch
86
Photo
88
Thin film
90
Statistic chart
Value
time
92
Step
Arg
Std
Cp
Cpk
...
Step number
Step number
Step number

Fig. 7

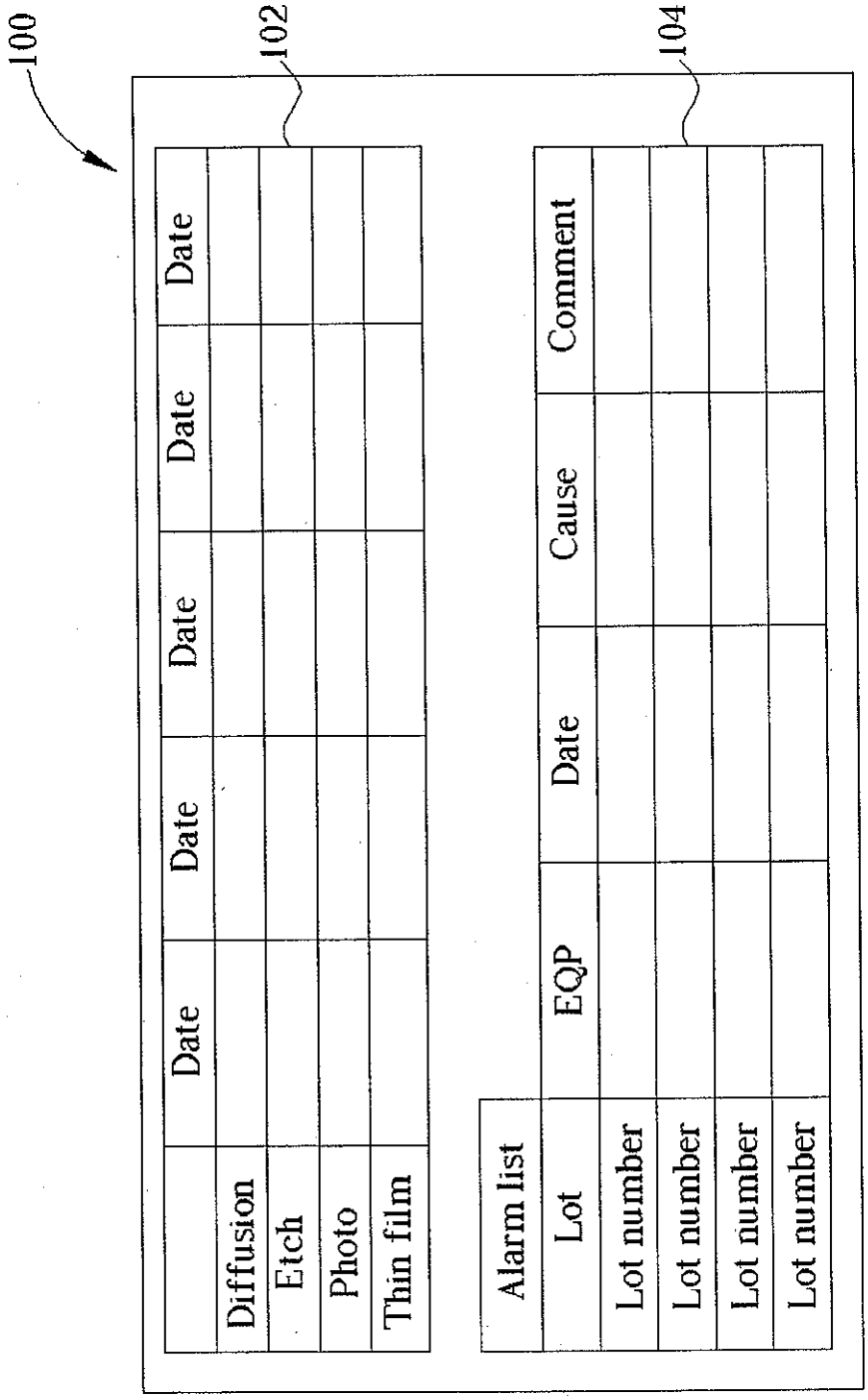

100
102
104
Date
Date
Date
Date
Date
Diffusion
Etch
Photo
Thin film
Alarm list
Lot
EQP
Date
Cause
Comment
Lot number
Lot number
Lot number
Lot number

Fig. 8

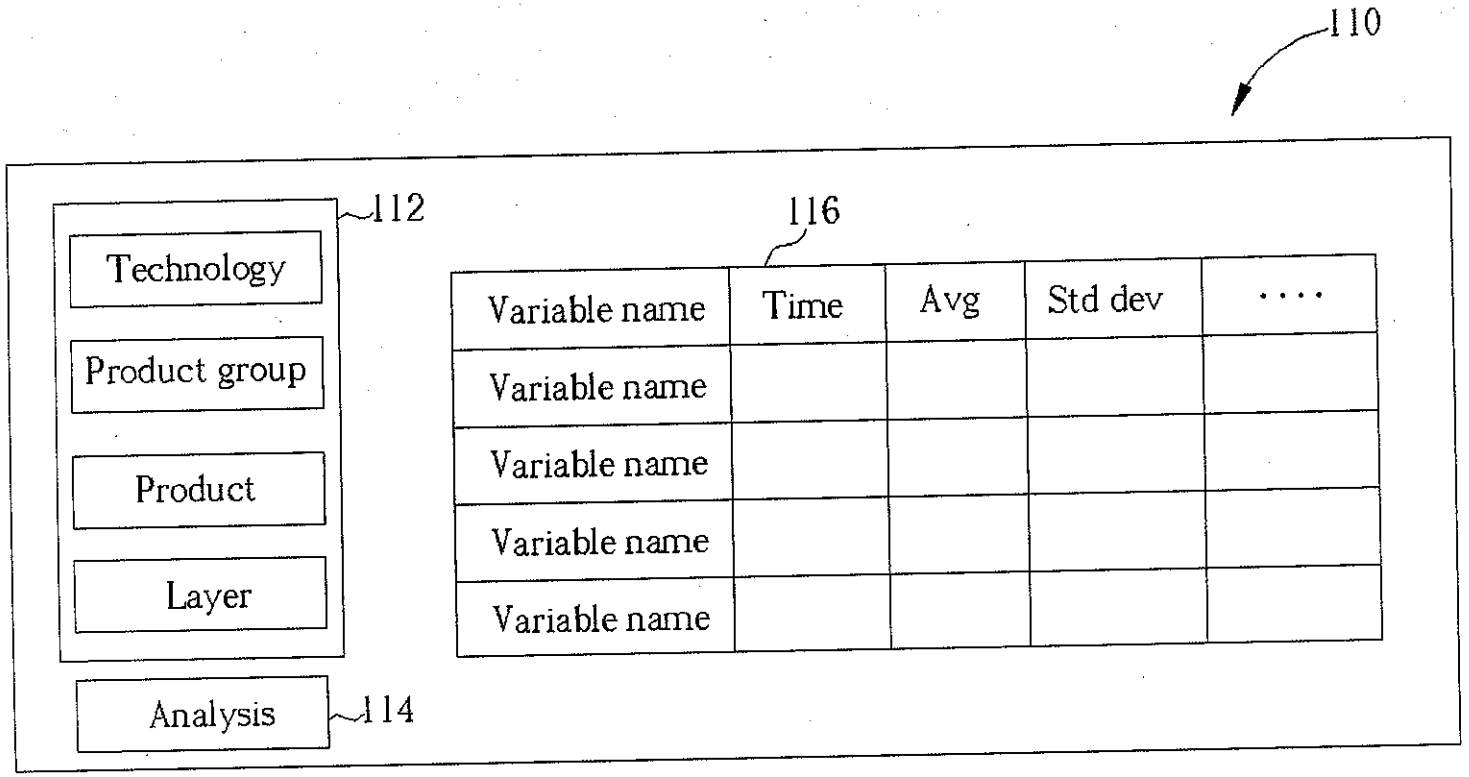

110
112
Technology
Product group
Product
Layer
Analysis
114
116
Variable name
Time
Avg
Std dev
....
Variable name
Variable name
Variable name
Variable name

Fig. 9

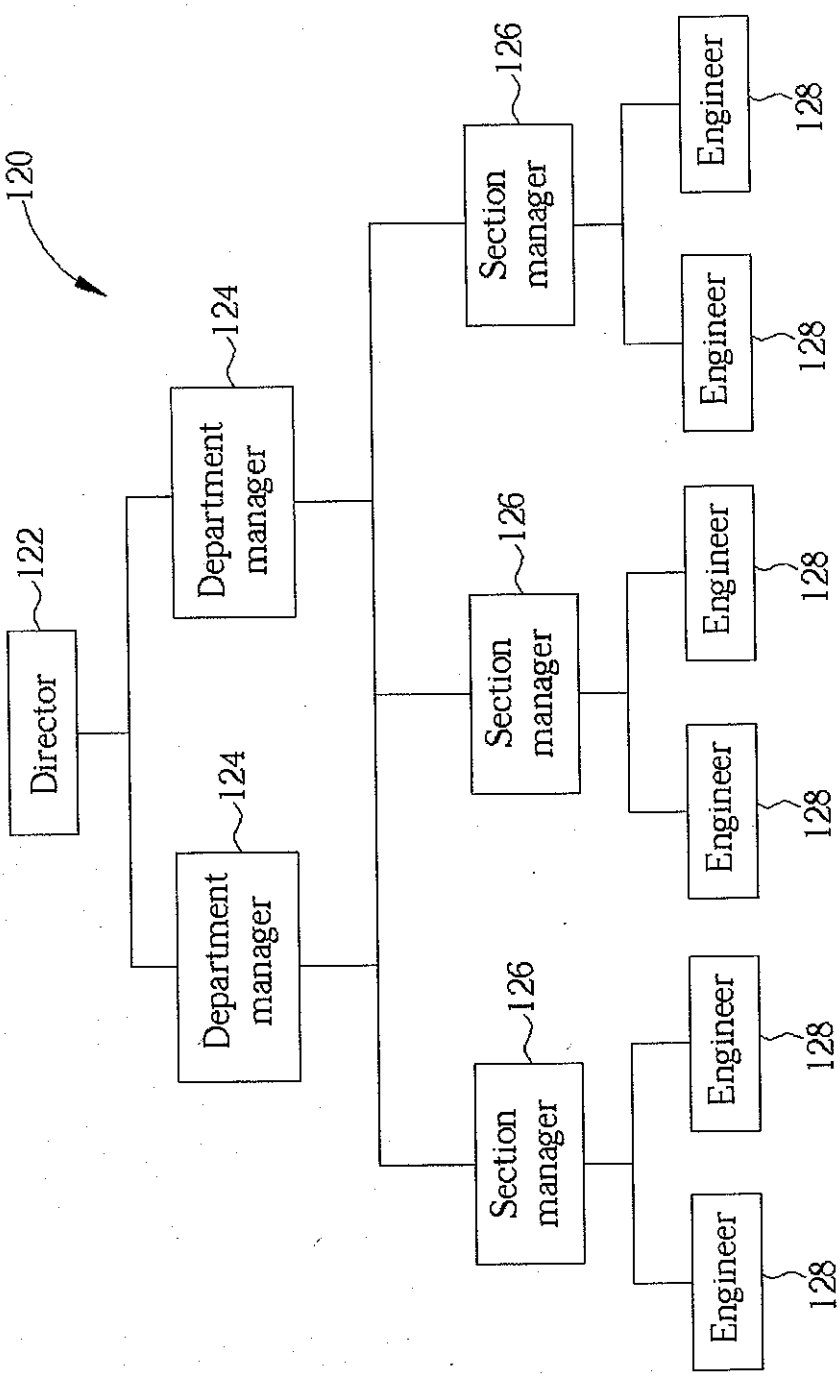

120
Director
122
Department manager
124
Department manager
124
Section manager
126
Section manager
126
Section manager
126
Engineer
128
Engineer
128
Engineer
128
Engineer
128
Engineer
128
Engineer
128

Fig. 10